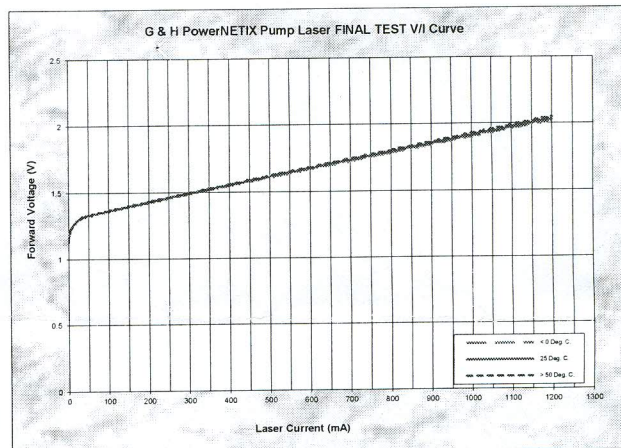
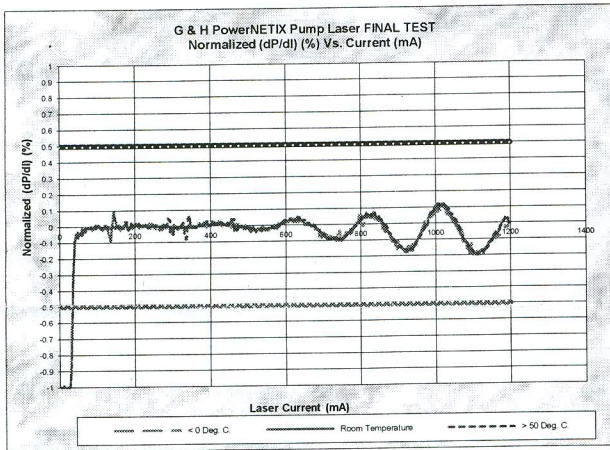
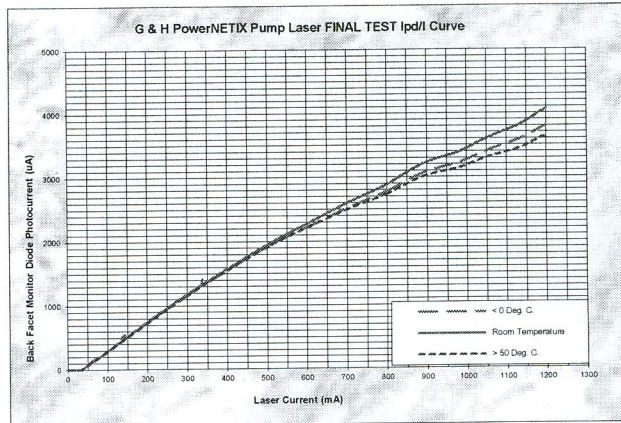
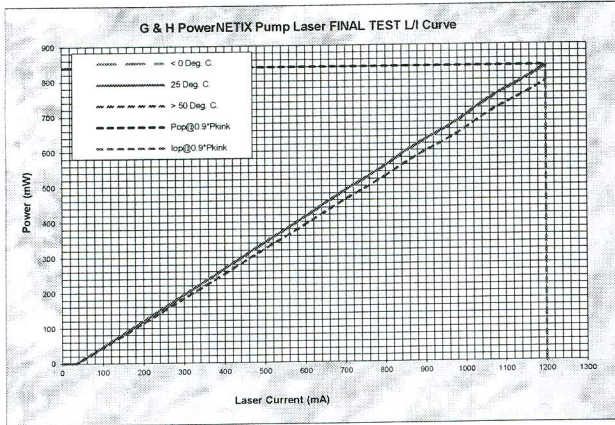


Chip Serial #
Module Serial #

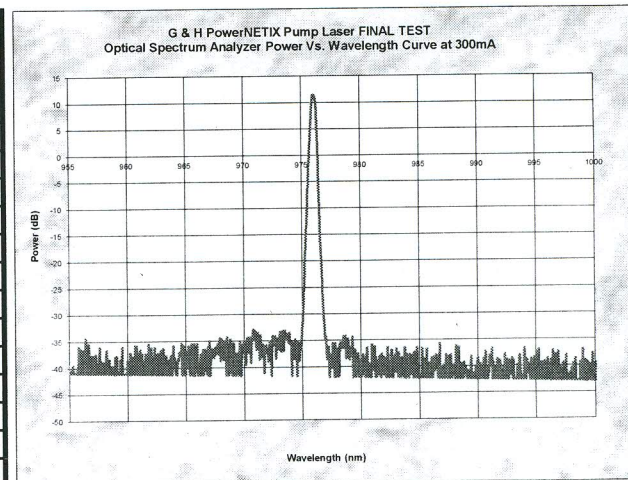
NA
D1412168

Time and Date of Test

8:18 AM on 2/5/2015



Module Test Parameters				
Case Temperature	-20.0	25.0	75.0	Deg. C.
Device Temperature	24.6	24.9	25.9	Deg. C.
Pkink	836	840	795	mW
Ikink	1200	1200	1200	mA
Drive Current at 600mW	856	853	902	mA
Pop = 0.9 * Pkink	836	840	795	mW
Iop @ 0.9 * Pkink	1200	1200	1200	mA
Vop @ 0.9 * Pkink	2.02	2.03	2.05	V
Ipd @ 0.9 * Pkink	3797	4065	3637	uA
Threshold Current	34.5	34.5	34.5	mA
Slope Efficiency @ 0.9 * Pkink	0.74	0.75	0.70	mW/mA
Slope Efficiency @ 300mA	0.72	0.73	0.66	mW/mA
TEC Current @ 0.9 * Pkink	-1338	439	3630	mA
TEC Voltage @ 0.9 * Pkink	-1.40	0.36	3.89	V
Center Wavelength @ 0.9 * Pkink	976.2	976.2	976.2	nm
Center Wavelength @ 300mA	976.2	976.1	976.1	nm



Calibration: G & H maintains a comprehensive instrumentation maintenance, test, and calibration program. Calibration services are provided by the original instrument manufacturers or independent calibration laboratories, as appropriate. All measurements are based on currently calibrated instruments, and are traceable to the U.S. National Institute of Standards and Technology (NIST).

Repeatability: Measurements of the fiber Bragg grating (FBG) stabilized sources are subject to variations in LI and Ipd due to changes in the orientation (coiling, bending, etc...) of the fiber between the source and the FBG. In order to best reproduce the recorded data, the user should orient the fiber pigtail so as not to exceed +/- 10% of the Ipd recorded for the specified operation drive current, Iop.